Product Change Notification: CAAN-24HCTT861

Date:

15-Apr-2025

Product Category:

Capacitive Touch Sensors

Notification Subject:

CCB 7418 Final Notice: Qualification of MTAI as a new final test site for selected CAP1203, CAP1206, CAP1208, CAP1293, CAP1296 and CAP1298 device families available in 8L and 14L SOIC (.150in) packages.

Affected CPNs:

CAAN-24HCTT861_Affected_CPN_04152025.pdf
CAAN-24HCTT861_Affected_CPN_04152025.csv

PCN Status: Final Notification

PCN Type: Manufacturing Change

Microchip Parts Affected: Please open one of the files found in the Affected CPNs section.
Note: For your convenience Microchip includes identical files in two formats (.pdf and .xls)

Description of Change: Qualification of MTAI as a new final test site for selected CAP1203, CAP1206, CAP1208, CAP1293, CAP1296 and CAP1298 device families available in 8L and 14L SOIC (.150in) packages.

Pre and Post Summary Changes:

	Pre Change	Post Change
Final Test Site	Sigurd – Taiwan (SIGT)	Microchip Technology Thailand (HQ) (MTAI)
Packing Method/Material	No change.	

Impacts to Datasheet: None

Change Impact: None

Reason for Change: To improve on-time delivery performance and manufacturability by qualifying MTAI as a new final test site.

Change Implementation Status: In Progress

Estimated First Ship Date: 06 June 2025 (date code: 2523)

Note Below EFSD: Note: Please be advised that after the estimated first ship date customers may receive pre and post change parts.

Timetable Summary:

	February 2025					**>**	**April 2025**					>	**June 2025**			
Work Week	05	06	07	08	09		14	15	16	17	18		23	24	25	26
Initial PCN Issue Date					X											
Qual Report Availability									X							
Final PCN Issue Date									X							
Estimated Implementation Date													X			

Method to Identify Change: Traceability Code

Qualification Report: Please open the attachments included with this PCN labeled as PCN_#_Qual_Report.

Revision History:

February 26, 2025: Issued initial notification.
April 15, 2025: Issued final notification. Attached Qualification Report. Provided Estimated first ship date on June 06, 2025.

Note: The change described in this PCN does not alter Microchip's current regulatory compliance regarding the material content of the applicable product.

Attachments:

PCN_CAAN-24HCTT861 Qual Report.pdf

Please contact your local **Microchip sales office** with questions or concerns regarding this notification.

Terms and Conditions:

If you wish to receive Microchip PCNs via email please register for our PCN email service at our **PCN home page** select register then fill in the required fields. You will find instructions about registering for Microchips PCN email service in the **PCN FAQ** section.

If you wish to change your PCN profile, including opt out, please go to the **PCN home page** select login and sign into your myMicrochip account. Select a profile option from the left navigation bar and make the applicable selections.

Affected Catalog Part Numbers (CPN)

CAP1206-1-SL

CAP1203-1-SN

CAP1293-1-SN

CAP1296-1-SL

CAP1296-1-SL-TR

CAP1203-2-SN-TR

CAP1208-1-SL

CAP1298-1-SL

CAP1298-2-SL-TR

CAP1298-1-SL-TR

CAP1293-2-SN-TR

CAP1203-1-SN-TR

CAP1293-1-SN-TR

CAP1208-2-SL-TR

CAP1206-1-SL-TR

CAP1206-2-SL-TR

CAP1208-1-SL-TR

QUALIFICATION REPORT SUMMARY

PCN #: CAAN-24HCTT861

Date:
April 11, 2025

Qualification of MTAI as a new final test site for selected CAP1203, CAP1206, CAP1208, CAP1293, CAP1296 and CAP1298 device families available in 8L and 14L SOIC (.150in) packages.

Purpose: Qualification of MTAI as a new final test site for selected CAP1203, CAP1206, CAP1208, CAP1293, CAP1296 and CAP1298 device families available in 8L and 14L SOIC (.150in) packages.

CCB No.: 7418

Test Name	Test Conditions	Sample Size	Qty of Lots	Fail/Accept Criteria	Results
Datalog/Bin Comparison	-Compare test numbers, test names, test sequence bin assignments & pass/fail -Accept if all match or justify the differences	5000	1	0.1%	PASSED
Site by Site verification	Verifies the channel map has the correct site assignments and tester/handler communications work correctly	33	1	≤10%	PASSED
Correlation Lot report	-Yield comparison between systems and test sites. -Accept on yield match within 0.1%	33	1	0.1%	PASSED
Test stability	-50 loop test performed with no datalog delays -Accept on 0 fails	33	1	0.1%	PASSED
Parametric test stability verification	Use Real Time Statistics software	33	1	≤10%	PASSED